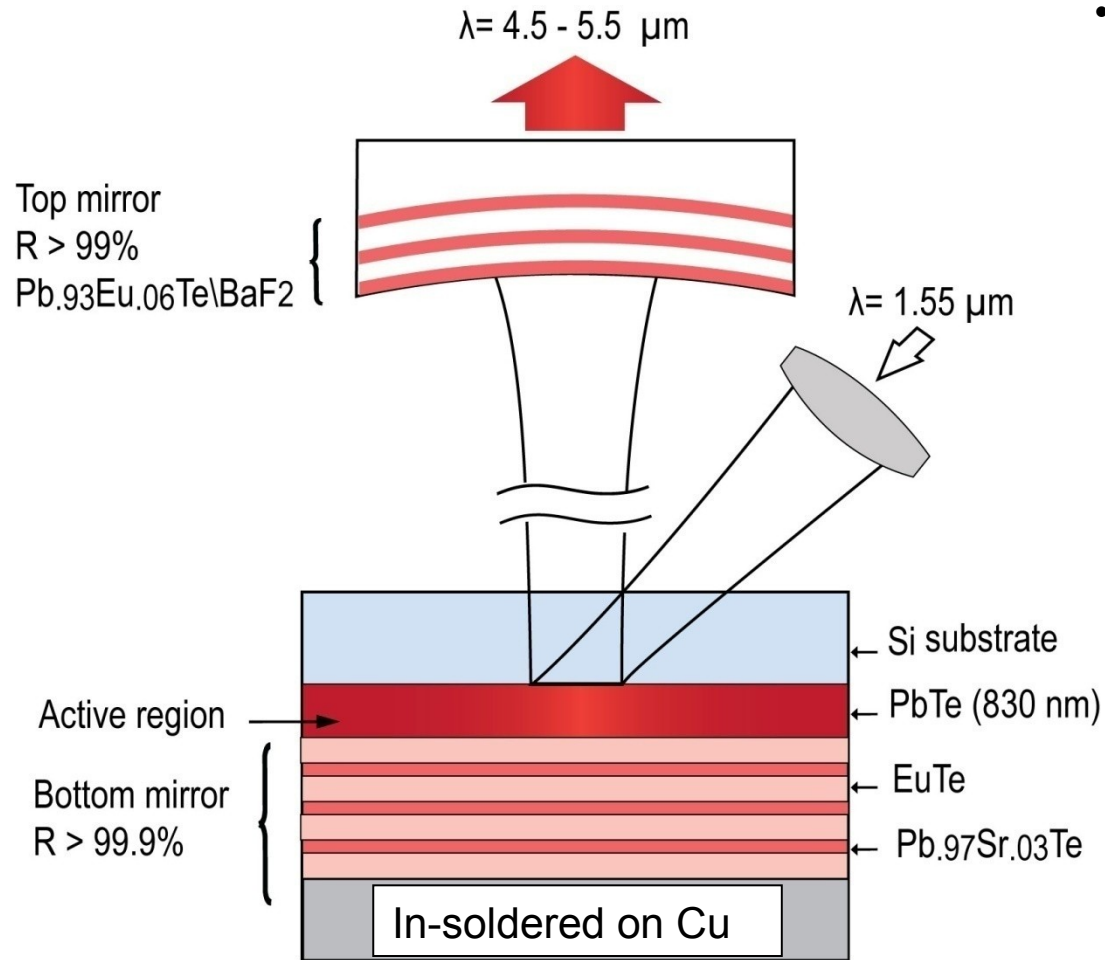


# PbTe VECSEL on Si

## VECSEL Design



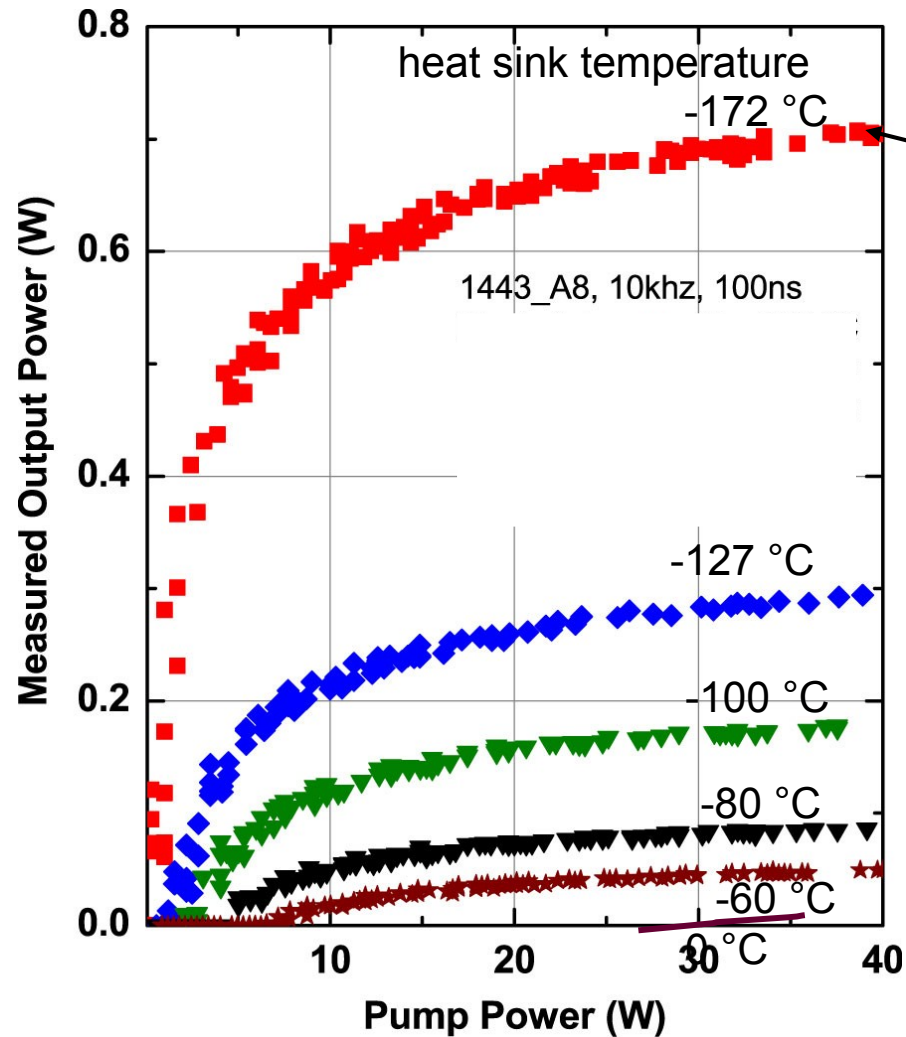
- resonant design for  $\sim 130\text{K}$

$$n_{\text{PbSrTe}} = \sim 5.7$$
$$n_{\text{EuTe}} = \sim 2.4$$

at 100 K

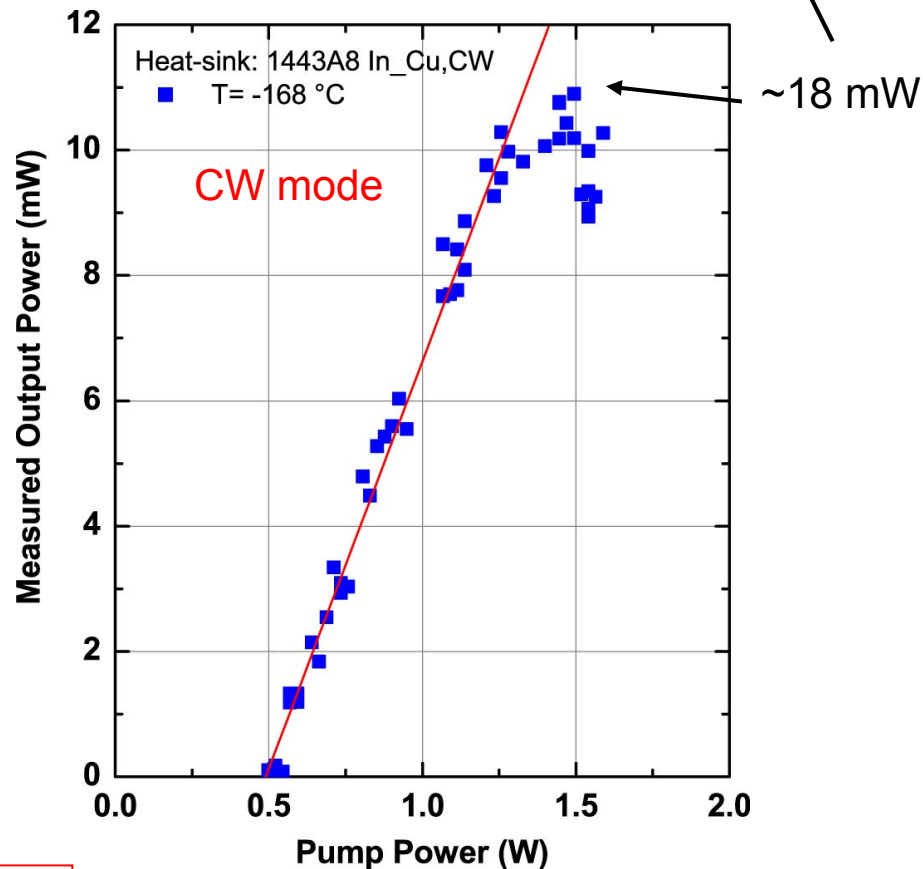
old results: Electr. Lett. 44, 2008: Si-sub was outside cavity, no soldering  
new: Si-sub *inside* cavity & In/Cu heat spreader

# PbTe VECSEL on Si



1.2 Watt (corrected for window/lens losses)

• Design for ~130K

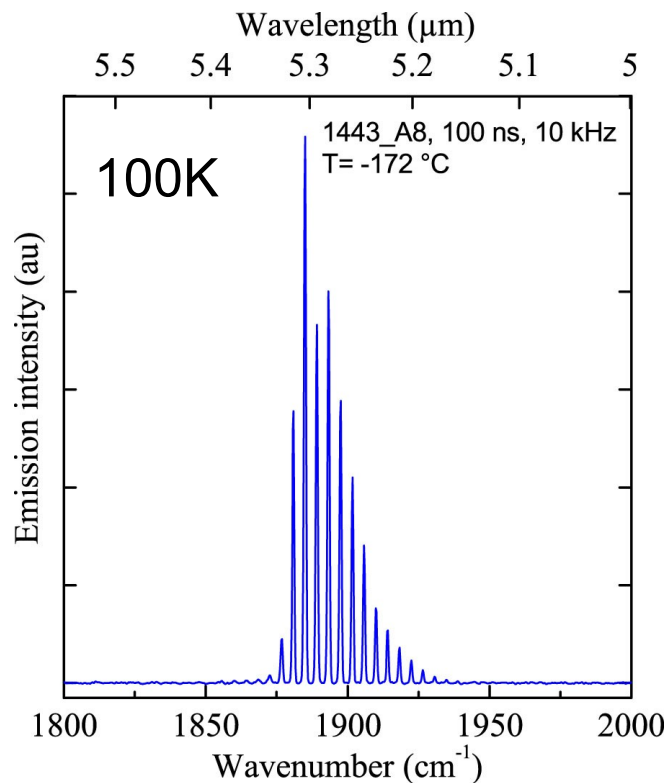


~18 mW

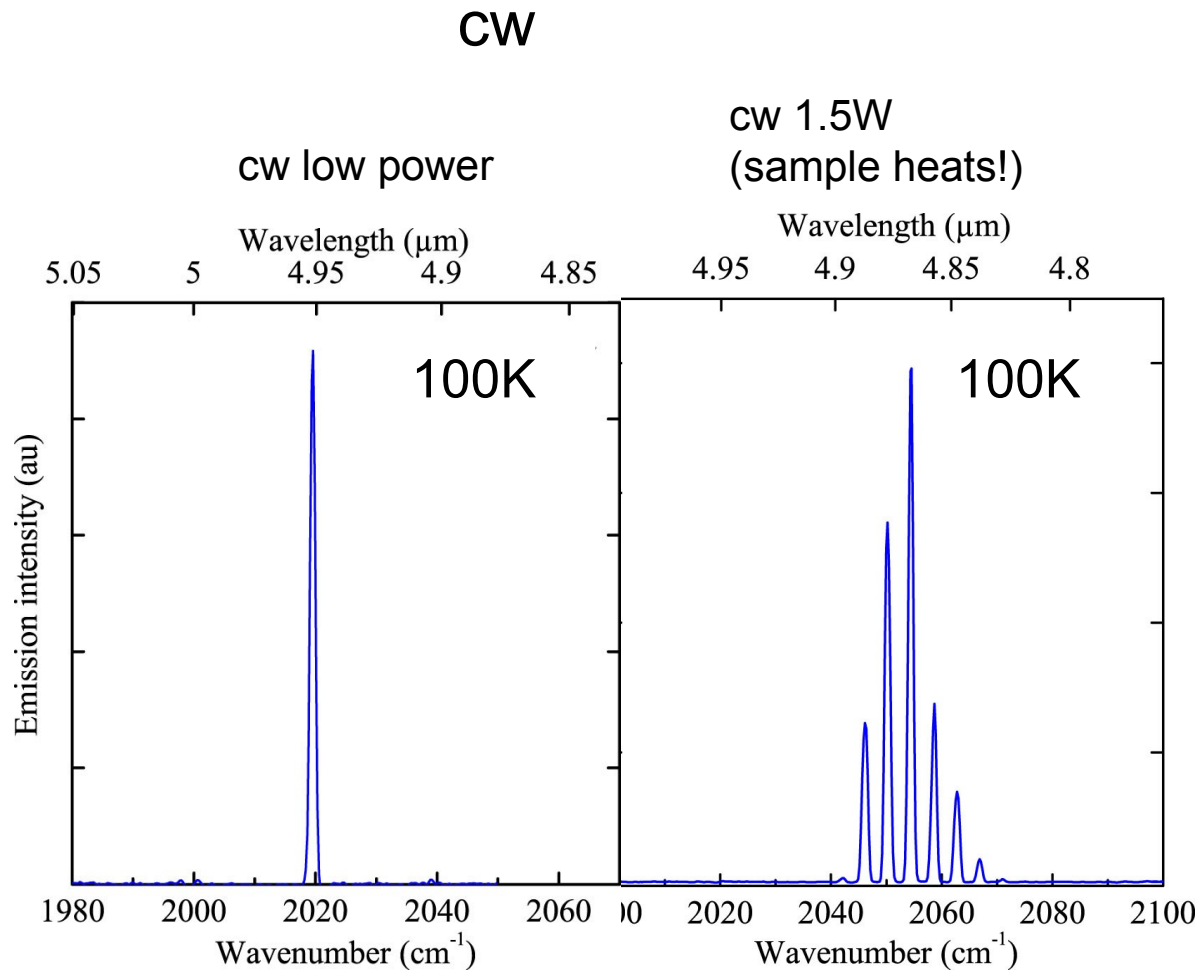
• cw at 100K – 140K

**Newest Results !**

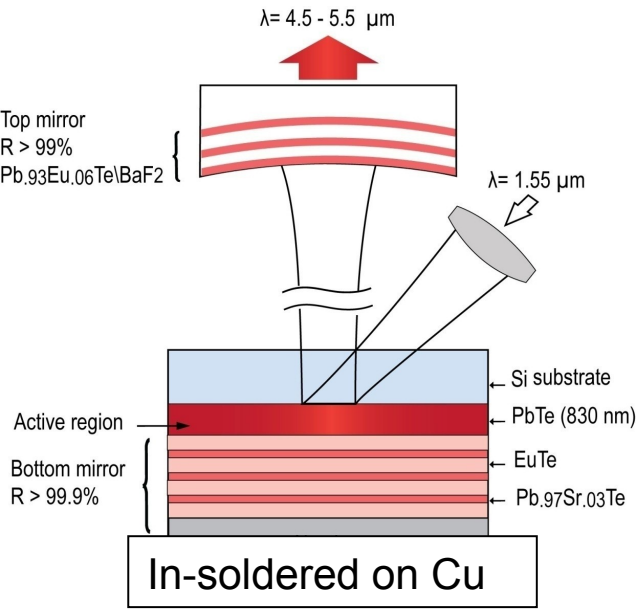
# PbTe VECSEL on Si: spectra



pulsed

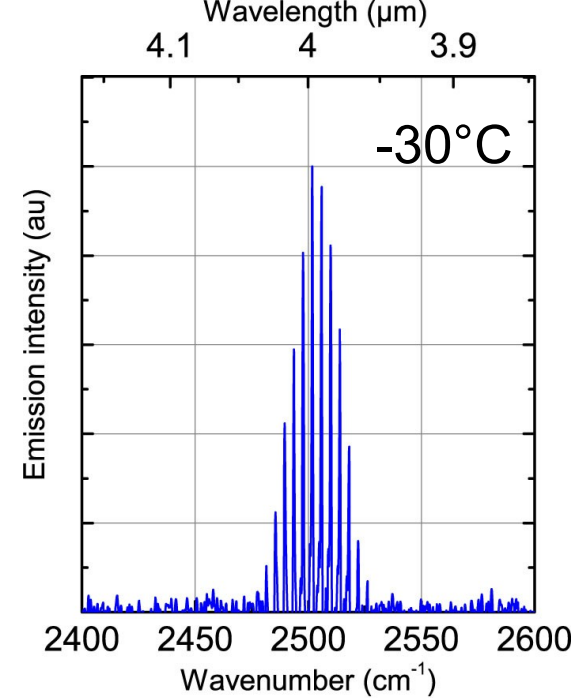


# PbTe VECSEL on Si



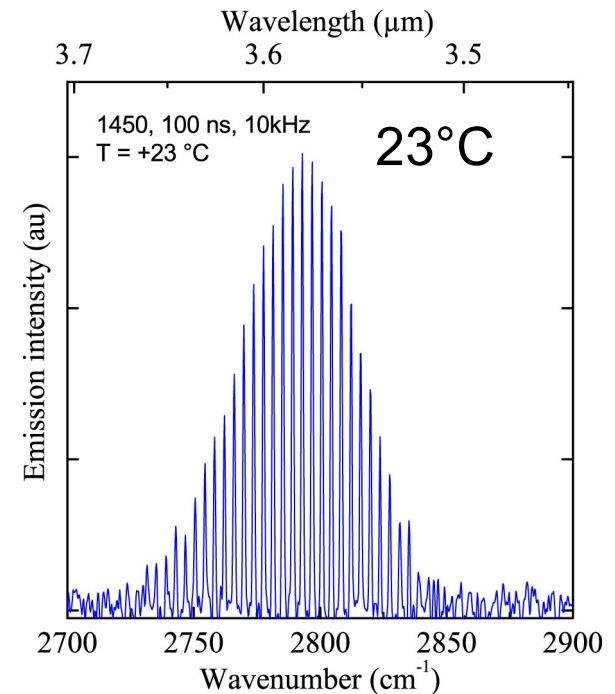
VECSEL design for 130K:  
(830 nm PbTe active layer)

lasing up to 0°C  
(heat sink temperature)



design for >200K:  
(600 nm PbTe active layer)

lasing up to 25°C  
(heat sink temperature)



higher n of substr → broader resonance peak → larger T-range

BaF<sub>2</sub>: n = 1.45 → Si: n = 3.5

ETH Zürich

Thin Film Physics Group

www.tfp.ethz.ch

# Beam Quality

Divergence Limit

$$\theta = M^2 \frac{\lambda}{\pi w_0}$$

$$M^2 = 1.3$$

$$\theta_{\perp, P} = 1.02$$

